







The new **QCA Series High-Speed Communication Analyzer** is a digital equivalenttime sampling oscilloscope with high quality precision timebase and low jitter mode designed to deliver a capable, cost-effective, and scalable test solution to address the requirements of next-generation high-speed interconnects and high-density ASICs.

With ultra-low jitter performance and unrivalled instrument density, the QCA Series is ideal for conducting high-precision measurements in parallel to optimize test throughout and reduce the cost-of test in high-volume manufacturing applications.

FEATURES

#### Low jitter

The high quality precision timebase with low jitter mode provides ultra-low jitter noise floor and PLL-based low frequency clock phase tracking, enabling precise measurement and characterization of high baud rate IO interfaces.



#### **Compact design**

The QCA-1000 Series enables high-density, high-channel count, test solutions in a relatively small footprint.



#### Cost-of-test

Improved test efficiency and test throughput can reduce the cost-of test and accelerate time-to-market.



#### Scalable

Designed to meet the requirements for high channel count validation and high-volume manufacturing and testing.



#### Ease of integration

Small footprint, remote control and API enable easy integration into probing and assembly equipment.



#### VISEYE<sup>™</sup> signal analysis software

The newly-designed visualization and analysis software has powerful analysis capabilities and is intuitive and easy-to-use.

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Accurate performance

predictive value (correlation) as the

prohibitively expensive R&D set-ups.

Comparable feature set and

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#### WHY IS LOW JITTER AND HIGH-CHANNEL-DENSITY SO IMPORTANT?

Next-generation high-speed interconnects as well as novel, densely packed processing, compute and switch ASICs play a critical role in the roll-out of hyperscale data centers and emerging HPC and AI applications. These next-generation devices will contain hundreds of channels, each requiring testing at all stages of development, validation and manufacturing.

This development presents a set of new challenges for the test engineer: how to manage the cost-of-test, while meeting significantly increased test requirements? Densely-integrated technologies have a compressed point of failure – so skipping testing is not a viable option. All channels will need to be validated to make sure they meet specifications.

High-speed oscilloscopes have been used to test transmitters for many decades and the tried-and-tested eye diagram, and derived analysis such as TDECQ remain the primary performance measurement and are still a bottleneck in today's design, validation and manufacturing chain. At high baud rates, when jitter is combined with amplitude (or signal) noise, limited bandwidth, and multi-level signalling such as PAM4, timing deviations and signal integrity can get exponentially worse, and error-free transmission will be impossible if jitter is not controlled.

To be able to properly characterize the quality of high-speed interfaces, it is important that the jitter noise floor of the test instrumentation is low enough to be able to measure the jitter of the devices under test. It's also important that measurement equipment can track low frequency variations of the embedded clock in the high-speed signal. So-called clock wander is typical in link technologies that rely heavily on digital signal processing at the receiver or other advanced signalling formats.

Consequently, ultra-low jitter noise floor and PLL-based low frequency clock phase tracking are essential to provide the precision measurement conditions necessary for accurate and repeatable characterization of 100G per channel and above HSIO interfaces.

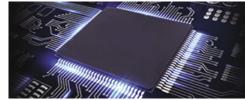
## JITTER MATTERS!

APPLICATIONS



Jitter and eye diagram testing for:

- Switch ASICs
- · GPUs/CPUs
- AI/ML processing ICs
  PAM4 DSPs
- Repeater/extender ICs
- Other high-speed ICs such as:
- DACs, TIAs, and drivers



- Electrical high-speed IO characterization
- High-volume test of high-speed ICs
- Validation testing
- Pre-production testing

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#### SOFTWARE - VISEYE

The QCA Series uses Quantifi Photonics' new VISEYE<sup>™</sup> Jitter and Eye-diagram analysis software for an intuitive & easy-touse experience to operate the oscilloscope and perform jitter and eye measurements.

VISEYE features a modern interface and has been designed to streamline the analysis process while providing full control of hardware and analysis functions. It also has a powerful API that allows streamlined automation for maximum measurement throughput.

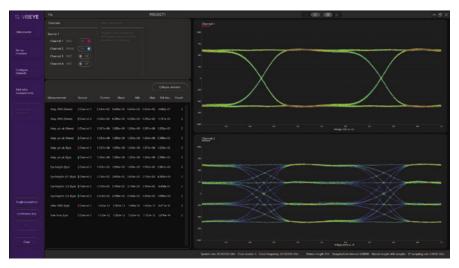


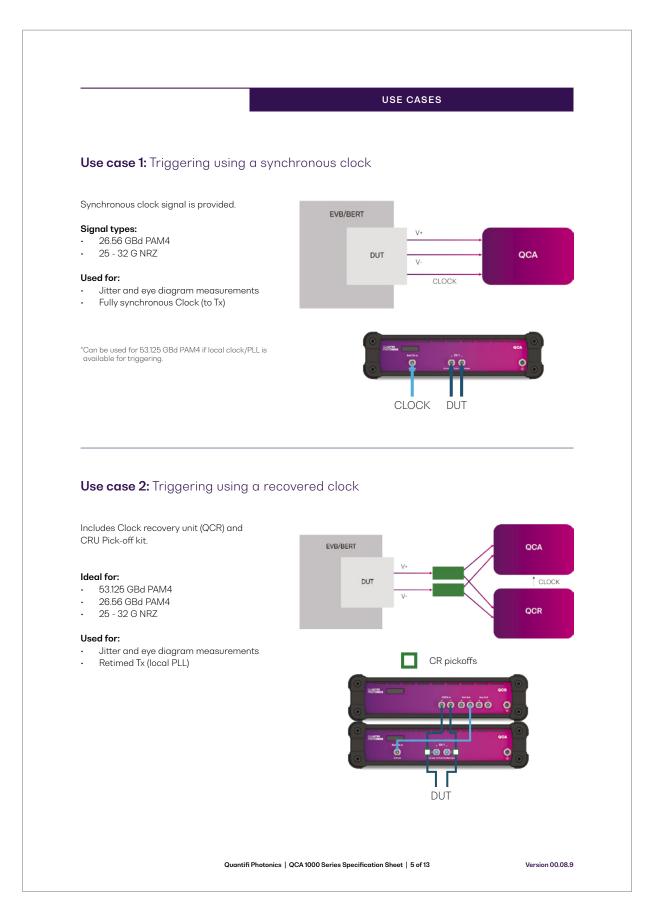
Image: 26 GBaud PAM4 eye diagram shown with numerical analysis parameters



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	DIMENSIONS
	Front view
60 mm	CULANTER PHOTONICS Ref Cite to 2 27 and 2 28 and L 14 Y pick phone logar 2 29 and 2 20 and
	۲ 244 mm
	Rear view
	Side view
ļ	327 mm
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#### QCA SERIES TECHNICAL SPECIFICATIONS

General Specifications	QCA	
Dimensions (HxWxD)	60 x 244 x 327 mm   2.36 x 9.6 x 12.9 inches	
Weight	2.71 kg	
Bus connection	USB (instrument control), Ethernet (data transfer)	
Number of channels	1 or 2 differential	
Operating temperature range	5 °C to 45 °C   41 °F to 113 °F	
Storage temperature range	-40 °C to 70 °C   -40 °F to 158 °F	

Power Specifications	QCA
AC input voltage range	100 to 240 V
AC input current	1.3 A (115 V), 0.9 A (230 V)
AC frequency range	47 to 63 Hz

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#### QCA 1000 SERIES TECHNICAL SPECIFICATIONS

Model Number	1001	1002	
Electrical QCA			
Coupling	AC-coupled, differential or single-ended	AC-coupled, differential or single-ended	
Analog bandwidth (-3 dB)	32 GHz	50 GHz	
Equivalent-time sampling rate, max	3.5 MHz	3.5 MHz	
Pattern capture	Up to PRBS15	Up to PRBS15	
Front panel connectors	2.92 mm	2.4 mm	
Vertical			
RF termination	50 Ω (single-ended) 100 Ω (differential)	50 Ω (single-ended) 100 Ω (differential)	
RF connector	2.92 mm	2.4 mm	
Max input (damage threshold)	± 600 mV [each single-ended input]	± 600 mV [each single-ended input]	
Linear dynamic range (AC-coupled)	± 500mV (single-ended) 1000mV_pp (differential)	± 500mV (single-ended) 1000mV_pp (differential)	
Vertical noise floor - diff.	1.0 mV (rms)	1.4 mV (rms)	
Ref Clock Input		1	
RF termination	50 Ω	50 Ω	
RF connector	2.92 mm	2.92 mm	
Amplitude	300 - 750 mV_pp (≥ 10 GHz) 200 - 600 mV_pp (< 10 GHz)	300 - 750 mV_pp (≥ 10 GHz) 200 - 600 mV_pp (< 10 GHz)	
Frequency range	5 - 16 GHz	5 - 16 GHz	
Horizontal			
RMS jitter in low-jitter mode	150 fs	150 fs	

Notes Preliminary specs as of March 2024 and subject to change.

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#### VISEYET ADDITIONAL FEATURES

- Use up to eight sources of data, combined from the QCA instrument channels, captured waveform data files, or math waveforms
- Show up to eight plots in a grid or stack view, in waveform mode or eye diagram mode
- Use the project configuration file to capture your project settings to load it back easily for future use
- Save your measurements results and statistics as a CSV file for further analysis.
- Configure the eye diagram plots Select the heat map type, eye accumulation type, and the desired saturation intensity
- Apply chains of mathematical functions to existing sources

### **Math functions**

Add/Subtract	Invert	Absolute Value	Minimum
Subtract	Amplify	Average	AlignDelay
Multiply	Square	Median	Difference
Common Mode	Square Root	Max./Min.	Summation

#### Advanced math

S-parameter embedding and de-embedding (s2p me) Equalizer (CTLE) Equalizer (LFE)	S-parameter embedding and de-embedding (s2p file)	Continuous Time Linear Equalizer (CTLE)	Linear Feedforward Equalizer (LFE)
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#### Supported measurements

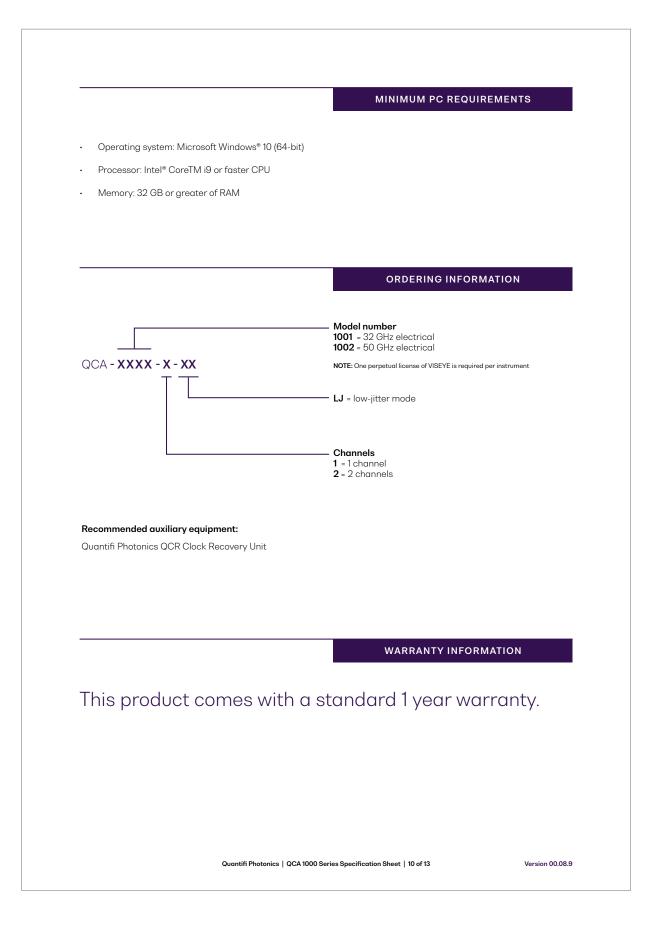
Amplitude average	Levels	Jitter RMS	Symbol period (Bit rate)
Amplitude peak-peak	Eye one level	One/Zero levels	Transmitter linearity (RLM)
Amplitude RMS	Eye skews	Rise time	
Eye amplitude	Eye width (NRZ/PAM4)	Signal-to-noise distortion ratio (SNDR)	
Eye crossing percentage	Eye zero level	Signal-to-noise ratio (SNR)	
Eye center amplitude	Fall time	Signal to noise ratio Q factor	
Eye height (NRZ/PAM4)	Jitter peak-peak	SNR Inter-symbol interference	

\*Future software updates will include additional measurement functions.

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#### CATALOGUE

Our portfolio of optical & electro-optical test modules is rapidly expanding to meet a wide range of customer requirements and applications.

#### **Tunable Laser Sources**

Versatile telecom laser sources with full tunability across C or L bands. Narrow 100 kHz linewidth, up to 16.5 dBm of power, optional whisper mode to disable frequency dither

#### Superluminescent Diode Broadband Light Source Super-luminescent LED light

source with high output power large bandwidth and low spectral ripple and various wavelengths.

#### Polarization Controller & Scrambler

High-speed automated polarization control with broad wavelength coverage from 1260nm to 1650nm, low insertion loss and back reflection. Full remote control via intuitive GUI LabVIEW or SCPI

#### **Optical Spectrum** Analyzer (OSA)

Cost-effective, spectral measurement in a compact module with built-in analysis for: SMSR, OSNR & spectral width. Targeted wavelengths for specific applications in O band, C band & L band.

#### Photonic Doppler Velocimeter (PDV)

Purpose-built module for Photonic Doppler Velocimetry (PDV), A circulator, two VOAs and a passive coupler all built into one compact module

PXI - MODULAR SYSTEM



Laser Sources Highly customizable laser platform. Select required wavelength, power and fiber type for a customized solution.

#### **Optical-to-Electrical** Converter

**Fixed Wavelength** 

High bandwidth, broadband O-to-E converter. Available in a range of configurations; choose from 1 or 2 channels, AC or DC coupling and various conversion gain and operating wavelength ranges.

#### **Optical Power Meters**

Fast terminating or inline monitoring of optical signal power from -60 to +10 dBm across 750 – 1700 nm wavelengths. Model with logarithmic analog output for applications such as silicon photonics fiber alignment.

#### **Passive Component** Integration

Integrate passive optical components of your choice such as WDM couplers, splitters, band-pass filters, PM beamsplitters and circulators. Models support SMF, MMF and PMF.

#### **Optical Switch** Proven reliability and fast

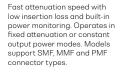
switching time. Wide variety of switch onfigurations: 1x4, 1x16, 16x16 and more. Models support SMF, MMF and PMF.



Wave Laser Swept, tunable continuous wave (CW) laser source with 0.01 dB power stability and 400 nm/s high-speed scan rate for R&D and production testing

Swept, Tunable Continuous

#### Variable Optical Attenuator (VOA)



Bit Error Rate Tester



4 or 8-channel Pulse Pattern Generator and Error Detector at rates up to 29 Gbps for the design, characterization and production of optical transceivers and opto-electrical components



Passive Component Storage Protect and store your own

passive fiber optic components such as splitters, connector adaptor patchcords, WDM couplers, and isolators in one handy module.





(BERT)





WHY CHOOSE QUANTIFI PHOTONICS

# Test. Measure. Solve™

Quantifi Photonics is transforming the world of photonics test and measurement. Our portfolio of optical and electrical test instruments is rapidly expanding to meet the needs of engineers and scientists around the globe. From enabling ground-breaking experiments to driving highly efficient production testing, you'll find us working with customers to solve complex problems with experience and innovation.

To find out more, get in touch with us today.

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